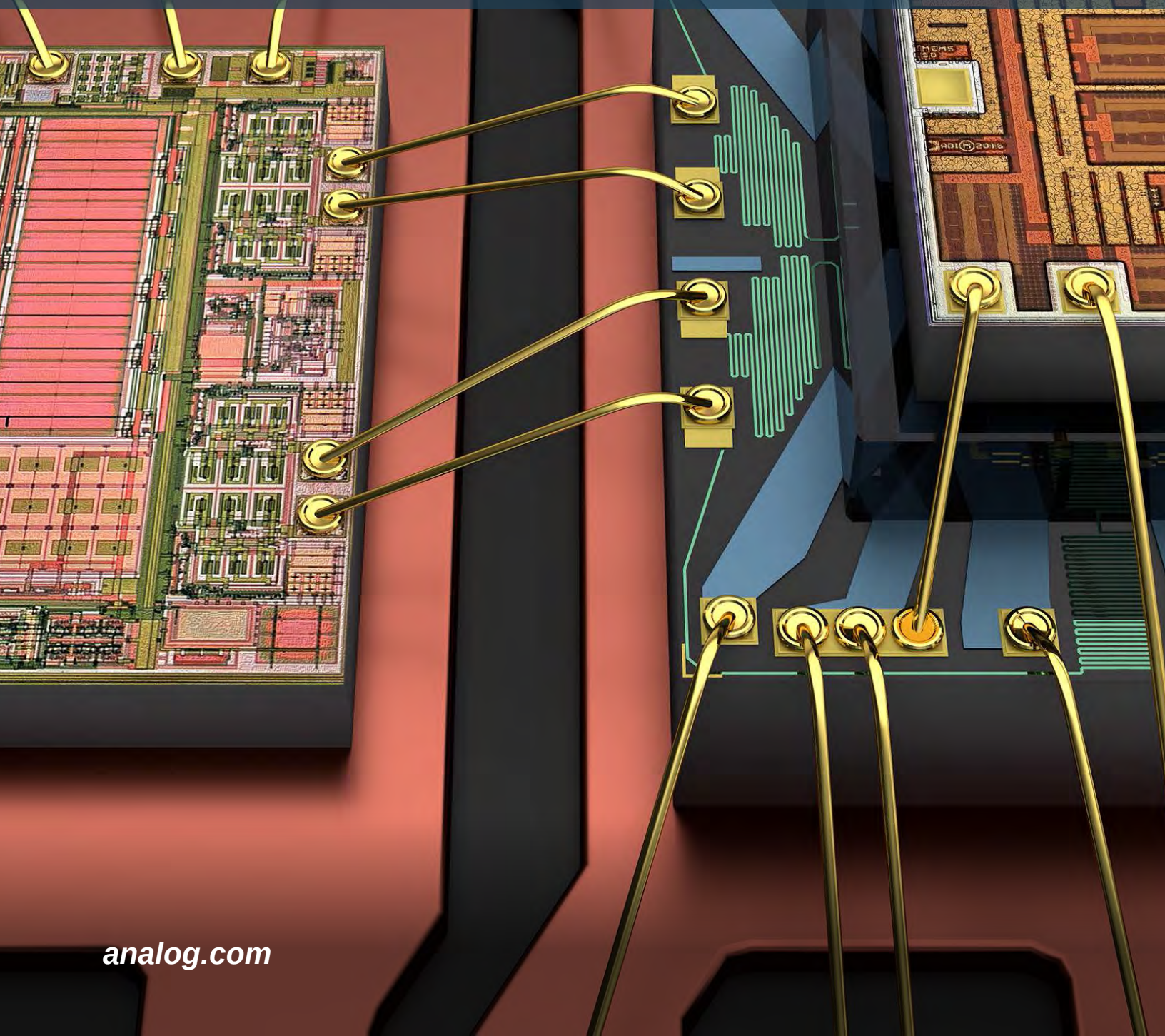
ANALOG DEVICES

AHEAD OF WHAT'S POSSIBLE™

RELIABILITY REPORT



analog.com

RELIABILITY DATA
LTC4271

1/10/2013

• OPERATING LIFE TEST

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE COE	NEWEST DATE CODE	K DEVICF HOURS (1) AT +125°C	NUMBER OF (2) FAILURES
QFN/DFN	154	1034	1052	89.94	0
	154			89.94	0

• PRESSURE COOKER TEST AT 15 PSIG, +121°C(5)

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS	NUMBER OF FAILURES
QFN/DFN	305	0823	0846	102.48	0
	305			102.48	0

• TEMP CYCLE FROM -65°C to +150°C(5)

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
QFN/DFN	297	0823	0846	297.00	0
	297			297.00	0

• THERMAL SHOCK FROM -65°C to +150°C(5)

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
QFN/DFN	275	0823	0937	194.50	0
	275			194.50	0

(1) Sample size is too small too calculate meaningful FIT rate. FIT rate given by Process Technology.
(2) Assumes Activation Energy = 0.7 Electron Volts
(3) Failure Rate Equivalent to +55°C, 60% Confidence Level = 18.68 FITS
(4) Mean Time Between Failures in Years = 6,112
(5) Mechanical data given by Process / Package family similarity
Note: 1 FIT = 1 Failure in One Billion Hours.